

Notice of References Cited	Application/Control No. 10/784,979	Applicant(s)/Patent Under Reexamination YACH ET AL.	
	Examiner SHEW-FEN LIN	Art Unit 2166	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,973,612	10-1999	Deo et al.	340/7.58
*	B	US-6,990,333	01-2006	Andrew et al.	455/414.1
*	C	US-7,243,130	07-2007	Horvitz et al.	709/207
	D	US-			
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	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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